Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/027,657	MEYER ET AL.	
Examiner	Art Unit	
Jia W. Lu	2611	

	SEAR	CHED	
Class	Subclass	Date	Examiner
375	347	5/2/2006	JL
	-		

INT	INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner	
375	347	5/2/2006	JL	
			-	

SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
ALL EAST DATABASES	5/2/2006	JL	